

## **Supporting Information**

# Towards plastic smart windows: optimization of indium tin oxide electrodes for the synthesis of electrochromic devices on polycarbonate substrates

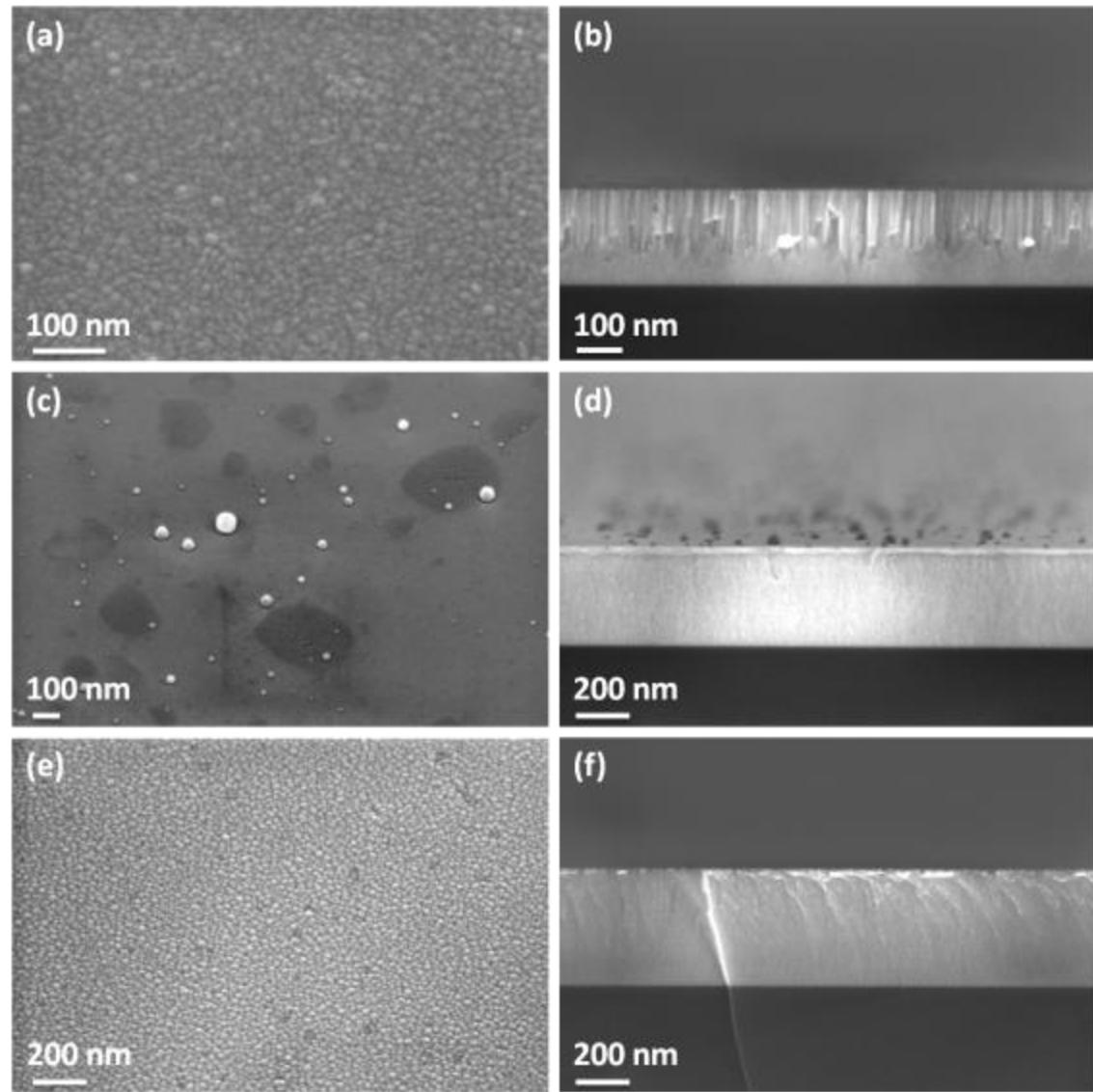
*Marco Laurenti,<sup>†,\*</sup> Stefano Bianco,<sup>†</sup> Micaela Castellino,<sup>§</sup> Nadia Garino,<sup>§</sup> Alessandro Virga,<sup>†</sup>  
Candido F. Pirri,<sup>†,§</sup> and Pietro Mandracci<sup>†</sup>*

<sup>†</sup>Department of Applied Science and Technology, Politecnico di Torino, C.so Duca degli Abruzzi 24, 10129 Torino, Italy

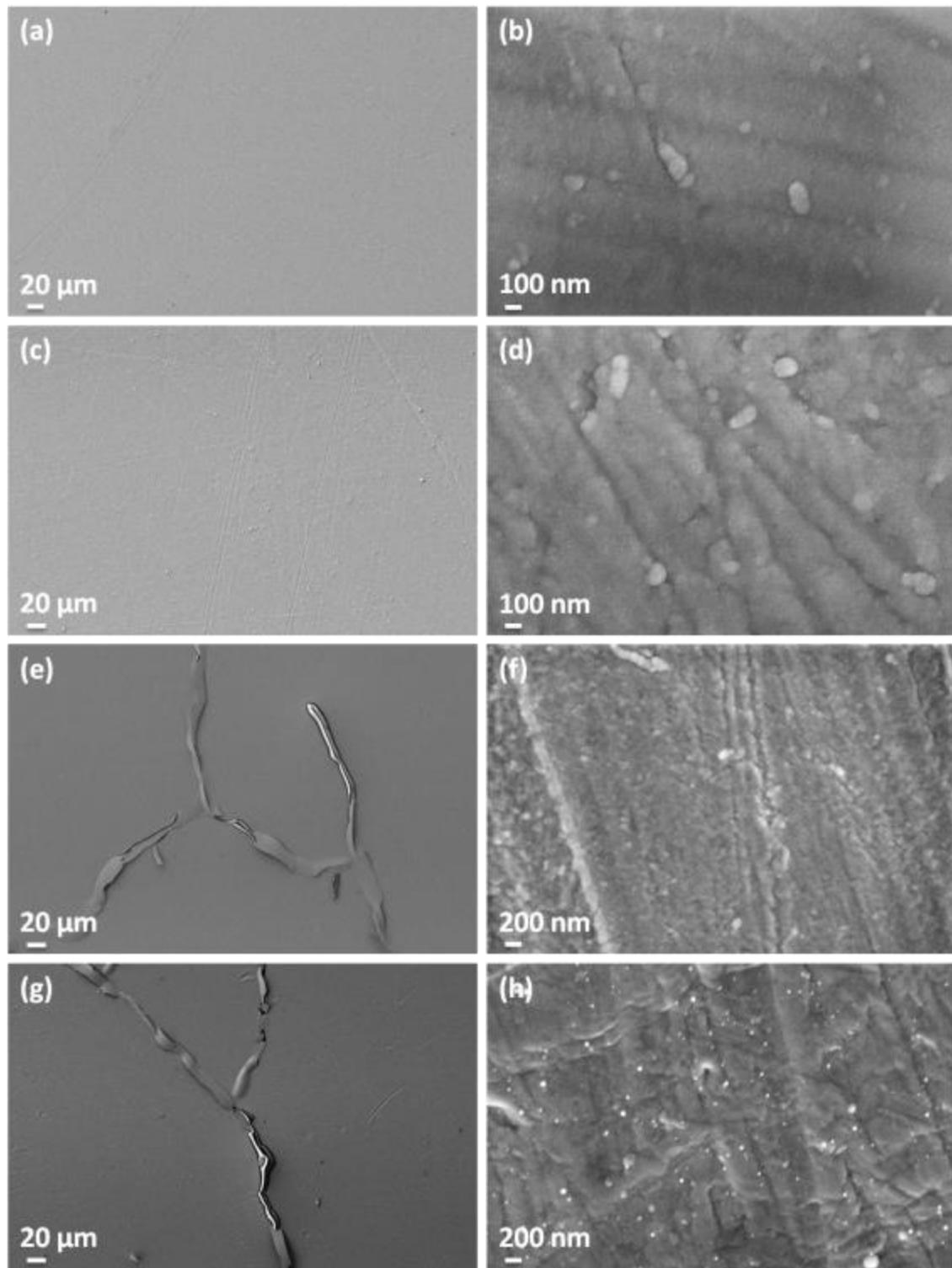
<sup>§</sup>Center for Space Human Robotics @ PoliTo, Istituto Italiano di Tecnologia, C.so Trento, 21, 10129 Torino, Italy

### **Corresponding Author**

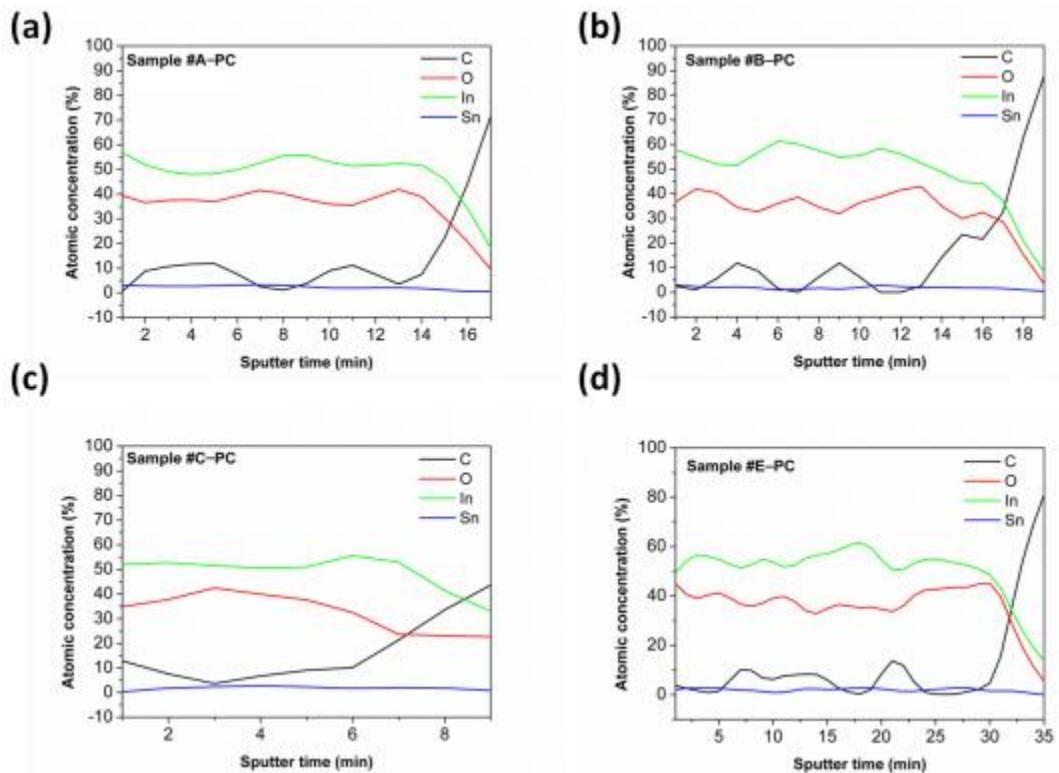
\*Phone: +39 011 090 7393. E-Mail: [marco.laurenti@polito.it](mailto:marco.laurenti@polito.it)



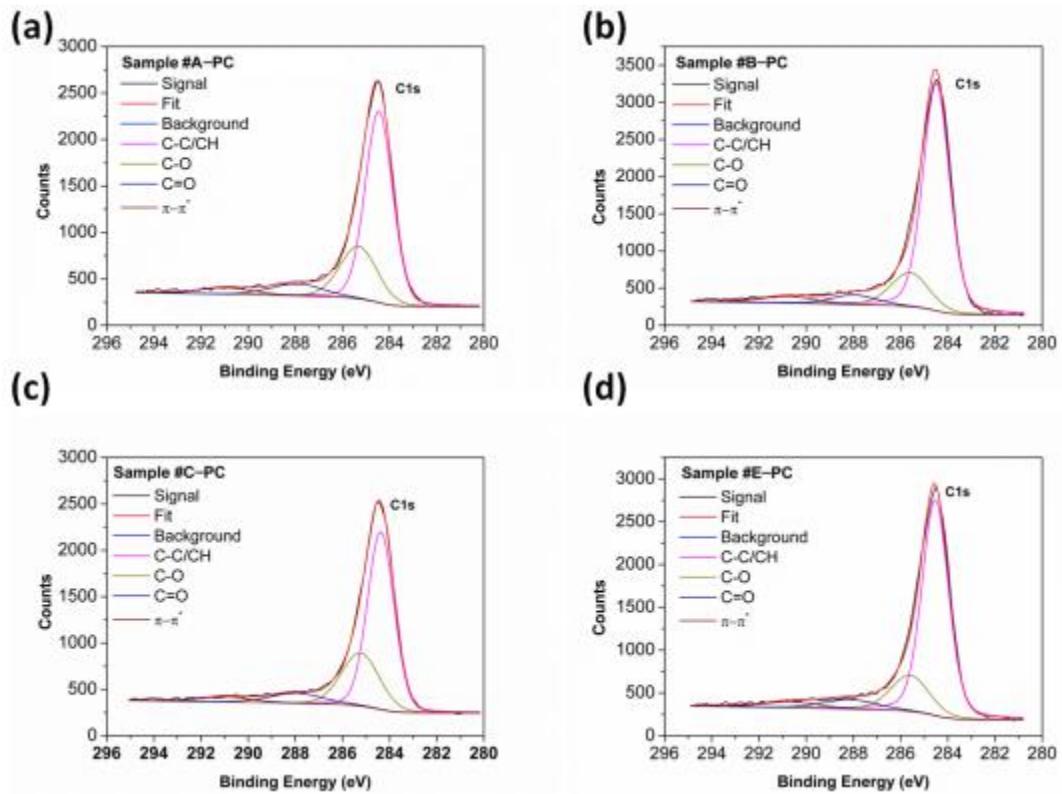
**Figure S1.** FESEM images showing the surface morphology and cross-sectional structure of samples #B-Si (a, b), #C-Si (c, d), and #E-Si (e, f). Sample #B-Si is deposited in a reactive atmosphere, while samples #C-Si and #E-Si in inert one.



**Figure S2.** FESEM images showing the surface morphology of samples #A-PC (a, b), #B-PC (c, d), #C-PC (e, f), and #E-PC (g, h), deposited on PC substrates. Samples #A-PC and #B-PC are grown in a reactive atmosphere, while samples #C-PC and #E-PC in inert one.



**Figure S3.** Depth-profile XPS analyses of ITO thin films grown on plastic PC substrates: samples #A-PC (a), #B-PC (b), #C-PC (c), and #E-PC (d).



**Figure S4.** High-Resolution C 1s XPS peaks collected at the ITO/PC interface, after depth profiling: samples #A-PC (a), #B-PC (b), #C-PC (c), and #E-PC (d).